

<b>Notice of References Cited</b>	Application/Control No. 08/764,110	Applicant(s)/Patent Under Reexamination CHEN, YUHPYNG L.	
	Examiner Mark L. Berch	Art Unit 1624	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0107343 A1	05-2005	Kasibhatla et al.	514/081
	B	US-2005/0038049 A1	02-2005	Ding et al.	514/265.1
	C	US-			
	D	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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